

Search Notes

Application/Control No.

10/711,593

Examiner

Benjamin P. Lee

Applicant(s)/Patent under
Reexamination

FAIRCHILD, MARK D.

Art Unit

3641

SEARCHED

Class	Subclass	Date	Examiner
244	199.2	11/2/2006	LEE
244	99.12	11/2/2006	LEE
244	198	11/2/2006	LEE
244	199.1	11/2/2006	LEE
244	199.3	11/2/2006	LEE
244	218	11/2/2006	LEE
244	219	11/6/2006	LEE
244	90R	11/6/2006	LEE
244	90A	11/6/2006	LEE
244	45R	11/6/2006	LEE

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search text: induce near5 yaw, aspect ratio near10 control or increase or decrease, vortex and yaw, induced near5 yaw	11/2/2006	LEE
reduce near10 downwash, aspect ratio near10 wing, rudderless, winglet, independent and winglet	11/6/2006	LEE
Search from Tim Collins		